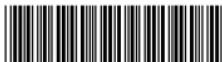


<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10572725	HAN ET AL.
<b>Examiner</b>	<b>Art Unit</b>	
Hsieh, Ping Y	2618	

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
455	76, 85, 86, 87, 118, 147, 148, 165.1, 183.1, 323, 324	11/12/08	PH

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
Text search in EAST (see search history)	11/12/08	PH
PLUS search	1/28/08	PH
Consulted with Yuwen Pan, Wen Huang	11/12/08	PH

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

/P. Y. H./  
Examiner.Alt Unit 2618